Unprecedented Speed Spee

The **S onix** provides the speed needed for a high-throughput industrial metrology system. With its high-speed camera and optimized optical and mechanical design, the **S onix** represents our fastest interferometric system. Measurement noise is maintained with the added bonus of improved resistance against vibration.

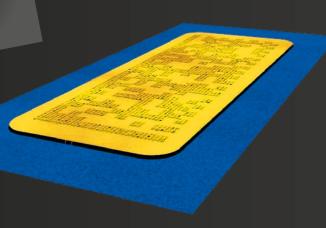


Resistance to











Objective lenses

Interferometric

Magnification	2.5X	5X	10X	20X	50X	100X
NA	0.075	0.13	0.30	0.40	0.55	0.70
WD (mm)	10.3	9.3	7.4	4.7	3.4	2.0
FOV¹ (μm)	5040 x 3780	2520 x 1890	1260 x 945	630 x 472	252 x 189	126 x 94
Spatial sampling² (μm)	7.88	3.94	1.97	0.98	0.39	0.19
Optical resolution³ (µm)	7.62	3.81	1.91	0.95	0.38	0.23
Measurement noise ⁴ (nm)						
Maximum slope ⁵ (°)	3	8	14	21	25	42

System specifications

Measuring principle	CSI			
Measurement types	Image, 3D and 3D thickness			
Camera	0.3 Mpx: 640 x 480 px (350 fps)			
Vertical scan range	Linear stage: 40 mm range; 2 nm resolution			
Max. Z measuring range	7 mm			
LED light sources	White (575 nm; center) and green (532 nm)			
Nosepiece	1 position (default) or 6 manual positions (optional)			
Sample reflectivity	0.05 % to 100%			
Advanced Software Analysis	Inc: SensoVIEW; Op: SensoPRO, SensoMAP			
Communication protocol	DLL; XML (optional)			
Computer	Latest INTEL processor			
Operating system	Microsoft Windows 10®, 64 bit			
Cable Length	5, 15 or 20 m			
Environment	Temperature 10 °C to 35 °C; Humidity $<$ 80 % RH; Altitude $<$ 2000 m			

Dimensions mm (inch)

Weight 3.6 kg (7.9 lbs)

